

Amendments to the Specification:

On page 5, line 21, replace the paragraph with the following:

4.  
2. The present invention satisfies the foregoing and other needs by providing an objective and repeatable approach to quantification of features from multidimensional image data. In a first aspect, the present invention provides methods, apparatuses, software and systems for image data analysis. A method of this first aspect may [comprising] comprise fitting a profile from a selected family of profiles to a selected portion of image data representing an imaged object, and computing a magnitude of an extension feature of the imaged object based on the fit profile.